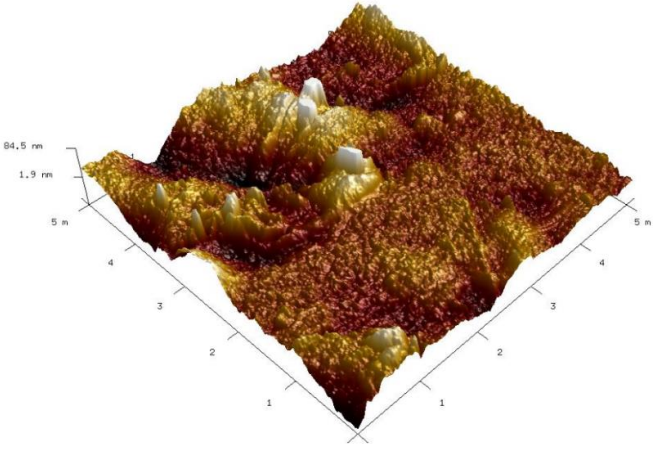
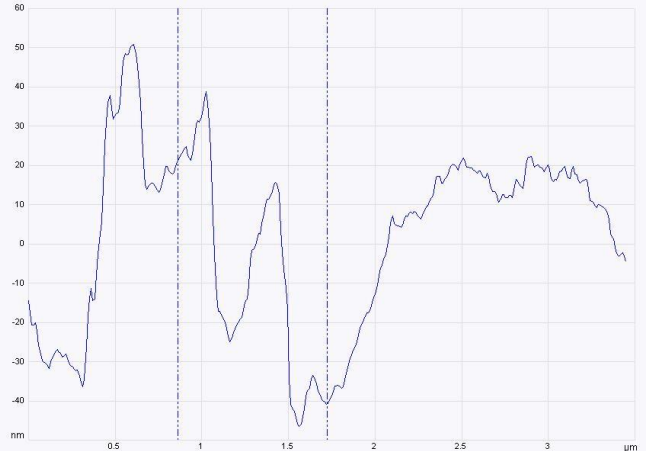

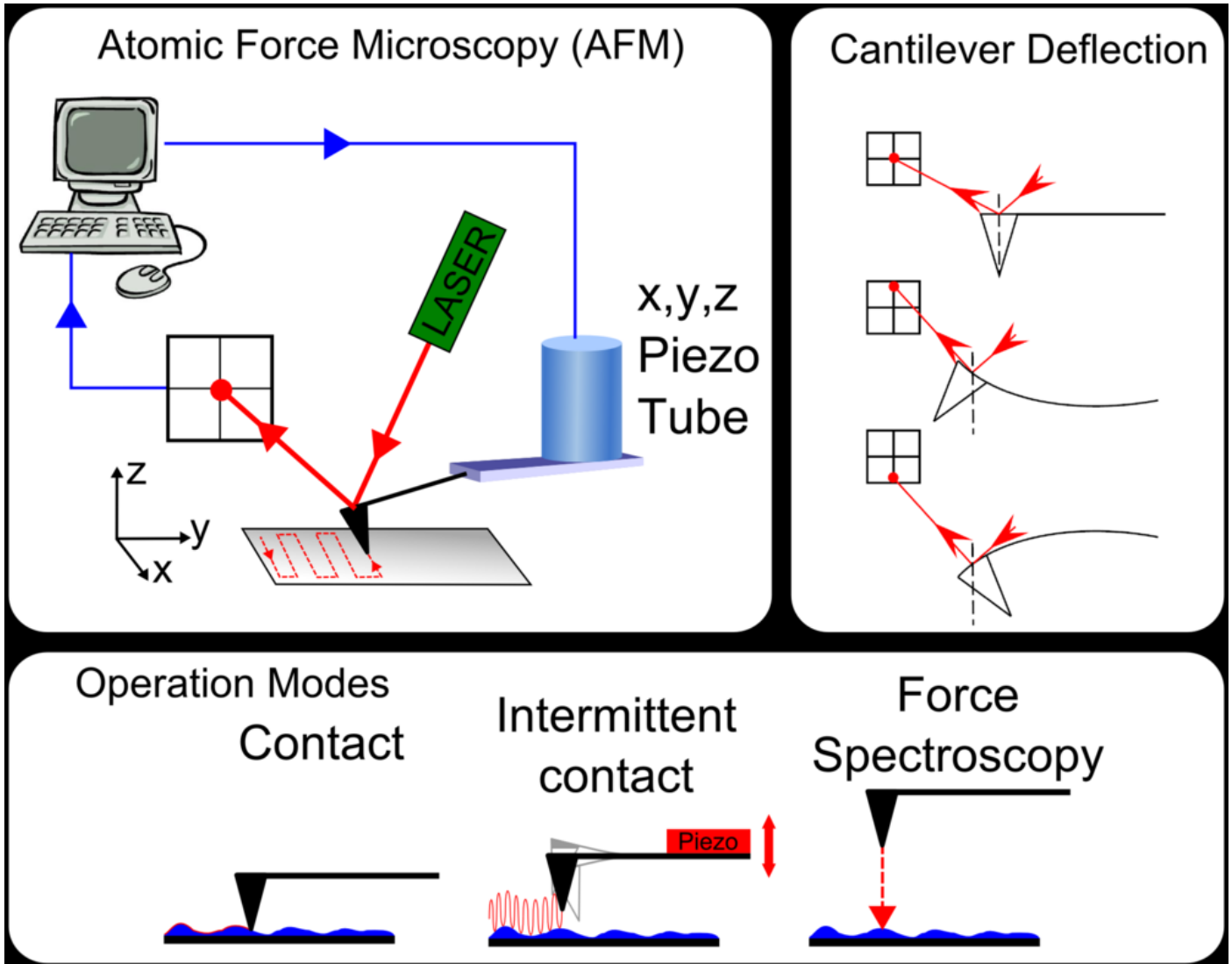


# 中原大學 薄膜中心 儀器簡介 - 6. AFM

<p>儀器編號：6</p> <p>中英文名稱 Bruker 加熱式 原子力顯微鏡 Thermo Atomic Force Microscopy, AFM</p> <p>廠牌/型號 Bruker / ICOM-2 SYS</p>	<p>功能</p> <ol style="list-style-type: none"> <li>1. 表面形貌、粗糙度分析</li> <li>2. 線、面高低分布分析</li> </ol>
<p>圖例-1</p> <p>表面形貌 3D 模型</p> 	<p>圖例-2</p> <p>表面粗糙度分析</p> <pre> Results Image Raw Mean  -0.000002 nm Image Mean      -0.000002 nm Image Z Range   226 nm Image Rq        22.0 nm Image Ra        16.3 nm Image Rmax      226 nm Raw Mean        0.00 nm Mean            0.00 nm Z Range         0.00 nm Rq              0.00 nm Ra              0.00 nm Roughness Rmax 0.00 nm Skewness        0.00 Kurtosis        0.00 Rz              0.00 nm Rz Count        0.00 Peak Count      0.00 Valley Count    0.00 Max Peak ht (Rp) 0.00 nm Average Max Height (Rpm) 0.00 nm Maximum Depth (Rv) 0.00 nm Average Max Depth (Rvm) 0.00 nm Line Density    0.00  Box X Dimension 0.00 Box Y Dimension 0.00                     </pre>
<p>圖例-3</p> <p>橫切高低分析</p> 	<p>儀器外觀</p> 

# AFM 檢測原理



<http://biomechanicalregulation-lab.org/afm/>